# **Data Release Production End to End Flow**

# Supporting documentation:

- LDM-151 has details on DRP algorithms.
- Data Release Production Overview
- Level 2 Calibrated Exposure Processing
- SUIT design

#### 02C.07.01.03 Pipeline Control and Infrastructure

- · Determine data to process
  - o per sky tract?
- Submit jobs to orchestration system
  - All visits can be generated in parallel
  - Then visits can be warped to tract WCS in parallel (some visits in multiple tracts)

#### 02C.04.03 PSF Estimation Pipeline

PSF varies spatially and with source brightness.

- Decompose PSF into atmospheric and telescope/camera components.
- Estimate telescope/camera component using wavefront sensor and metrology.
- Estimate atmospheric component by using bright, isolated stars.

### 02C.04.04 Image Coaddition Pipeline

- Basic snap/visit processing (02C.03.01):
  - Instrument signature removal
  - Cosmic ray rejection
  - Basic PSF determination
  - o Source extraction and basic WCS calibration
- Apply results of relative astrometric solution from Single Frame Pipeline
- Warp images to common coordinate system
- Co-add images, optionally with "background matching"

## 02C.04.05 Object Detection and Deblending

- · Detect sources on co-adds
- De-blend

### 02C.04.06 Object Characterization Pipeline

- Associate CoaddSources with Level 1 catalog and single frame catalog
- Source characterization:
  - Single-epoch characterization
  - Multifit
  - o Point source model fit
  - o Bulge-disk model fit
  - Trailed model fit
  - Dipole model fitCentroids
  - Adaptive moments
  - Petrosian and Kron fluxes
  - Aperture surface brightness
  - Resolved/unresolved object separation
  - Variability Characterization
- Forced photometry

## 02C.06.01.01 Catalogs, Alerts and Metadata

Databases used:

- Read:
  - o Level 1 Catalog
  - External Catalogs

- Read/Write:
- Catalogs from single frame processing
  Write (during DRP / Read by SUI):
   Object catalog
- - Forced Sources catalog

## 02C.05.02 Data Analysis and Visualization Tools

- Display and plot catalog from single visit
- Display cutout of deep coadd and associated catalog overlay.
- Display time-series for a selected source
- · Obtain provenance information for an Object (visits included, data release number, software versions used, associated alerts)



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